Search Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination
10/708,424	CHEN ET AL.
Examiner	Art Unit
Jeffrey S. Zweizig	2816

SEARCHED				
Class	Subclass	Date	Examiner	
327	308	2/9/2005	JZ	
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INTERFERENCE SEARCHED				
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
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